Applicant(s)/Patent Under Application/Control No. Reexamination 10/721,875 ENDO ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 2624 Alex Liew **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 382/144 01-2003 Sakai et al. US-2003/0021462 US-В US-С US-D

FOREIGN PATENT DOCUMENTS

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